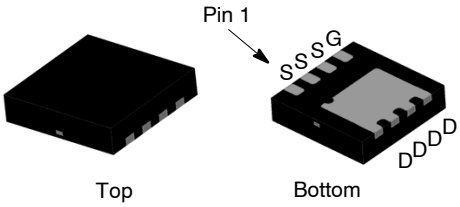
MOSFET – P-Channel, POWERTRENCH®

-30 V, -20 A, 10 mΩ

FDMC6679AZ



WDFN8 3.3x3.3, 0.65P
CASE 511DH

General Description

The FDMC6679AZ has been designed to minimize losses in load switch applications. Advancements in both silicon and package technologies have been combined to offer the lowest $r_{DS(on)}$ and ESD protection.

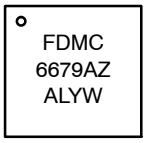
Features

- Max $r_{DS(on)}$ = 10 mΩ at V_{GS} = −10 V, I_D = −11.5 A
- Max $r_{DS(on)}$ = 18 mΩ at V_{GS} = −4.5 V, I_D = −8.5 A
- HBM ESD Protection Level of 8 kV Typical (Note 3)
- Extended V_{GSS} range (−25 V) for Battery Applications
- High Performance Trench Technology for Extremely Low $r_{DS(on)}$
- High Power and Current Handling Capability
- This Device is Pb−Free and Halide Free

Applications

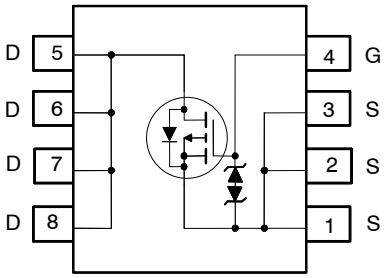
- Load Switch in Notebook and Server
- Notebook Battery Pack Power Management

MARKING DIAGRAM



FDMC6679AZ = Specific Device Code
A = Assembly Location
L = Wafer Lot Number
YW = Assembly Start Week

PIN ASSIGNMENT



ORDERING INFORMATION

See detailed ordering and shipping information on page 6 of this data sheet.

MOSFET MAXIMUM RATINGS (T_A = 25°C unless otherwise noted)

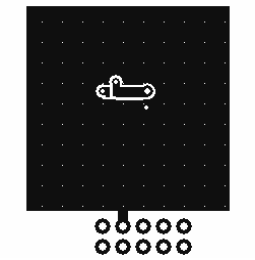
Symbol	Parameter			Rating	Unit
V_{DS}	Drain to Source Voltage			−30	V
V_{GS}	Gate to Source Voltage			±25	V
I_D	Drain Current	Continuous	T_C = 25°C	−20	A
		Continuous (Note 1a)	T_A = 25°C	−11.5	
		Pulsed		−32	
P_D	Power Dissipation		T_C = 25°C	41	W
	Power Dissipation (Note 1a)		T_A = 25°C	2.3	
T_J, T_{STG}	Operating and Storage Junction Temperature Range			−55 to + 150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

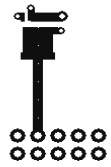
THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	3.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	53	

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in^2 pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR−4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a. 53°C/W when mounted on a 1 in^2 pad of 2 oz copper



b. 125°C/W when mounted on a minimum pad of 2 oz copper

2. Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.
3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = −250 μA, V_{GS} = 0 V	−30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = −250 μA, Referenced to 25°C		29		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = −24 V, V_{GS} = 0 V			−1	μA
		V_{DS} = −24 V, V_{GS} = 0 V, T_J = 125°C			−100	
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±25 V, V_{DS} = 0 V			±10	μA
ON CHARACTERISTICS						
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = −250 μA	−1.0	−1.8	−3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = −250 μA, Referenced to 25°C		−7		mV/°C
$r_{DS(on)}$	Static Drain to Source On Resistance	V_{GS} = −10 V, I_D = −11.5 A		8.6	10	mΩ
		V_{GS} = −4.5 V, I_D = −8.5 A		12	18	
		V_{GS} = −10 V, I_D = −11.5 A, T_J = 125°C		12	15	
g_{FS}	Forward Transconductance	V_{DS} = −5 V, I_D = −11.5 A		46		S
DYNAMIC CHARACTERISTICS						
C_{iss}	Input Capacitance	V_{DS} = −15 V, V_{GS} = 0 V, f = 1 MHz		2985	3970	pF
C_{oss}	Output Capacitance			570	755	pF
C_{rss}	Reverse Transfer Capacitance			500	750	pF
SWITCHING CHARACTERISTICS						
$t_{d(on)}$	Turn−On Delay Time	V_{DD} = −15 V, I_D = −11.5 A, V_{GS} = −10 V, R_{GEN} = 6 Ω		12	21	ns
t_r	Rise Time			14	25	ns
$t_{d(off)}$	Turn−Off Delay Time			63	100	ns
t_f	Fall Time			46	73	ns
Q_g	Total Gate Charge	V_{GS} = 0 V to −10 V, V_{DD} = −15 V, I_D = −11.5 A		65	91	nC
		V_{GS} = 0 V to −5 V, V_{DD} = −15 V, I_D = −11.5 A		37	52	nC
Q_{gs}	Gate to Source Charge	V_{DD} = −15 V, I_D = −11.5 A		8.7		nC
Q_{gd}	Gate to Drain “Miller” Charge			17		nC
DRAIN−SOURCE DIODE CHARACTERISTICS						
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0 V, I_S = −11.5 A (Note 2)		0.83	1.30	V
		V_{GS} = 0 V, I_S = −1.6 A (Note 2)		0.71	1.20	
t_{rr}	Reverse Recovery Time	I_F = −11.5 A, di/dt = 100 A/μs		31	49	ns
Q_{rr}	Reverse Recovery Charge			16	28	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

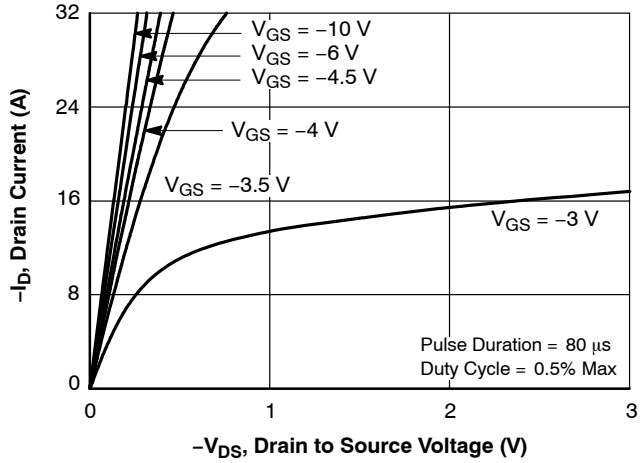


Figure 1. On Region Characteristics

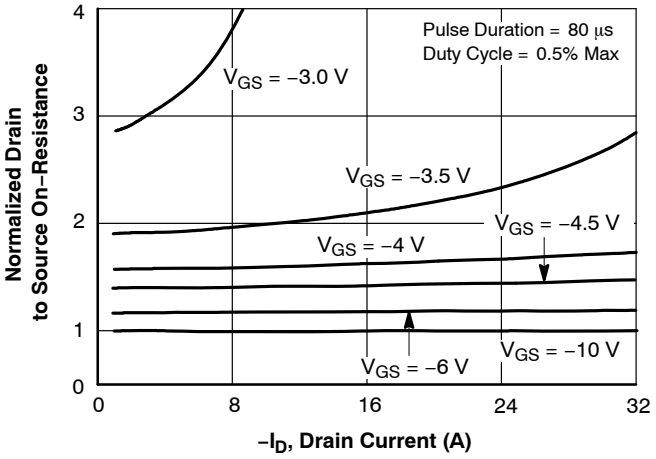


Figure 2. Normalized On−Resistance vs. Drain Current and Gate Voltage

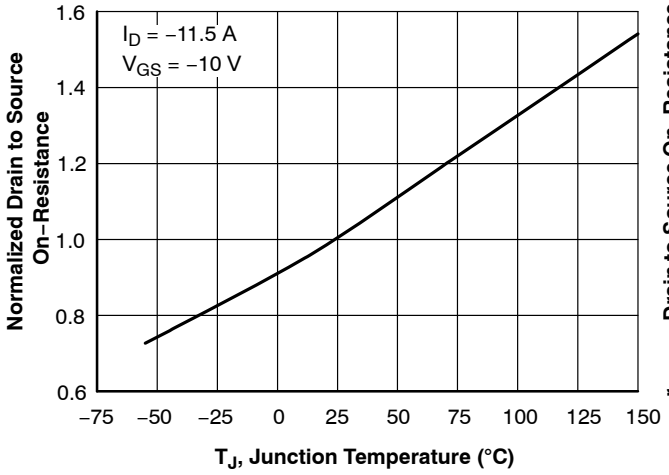


Figure 3. Normalized On Resistance vs. Junction Temperature

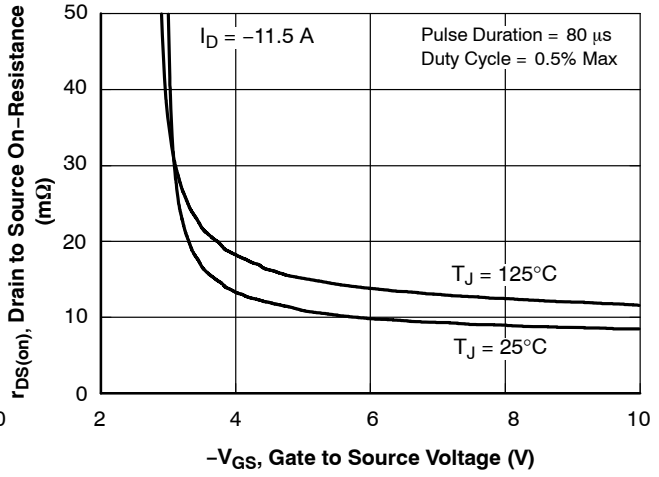


Figure 4. On−Resistance vs. Gate to Source Voltage

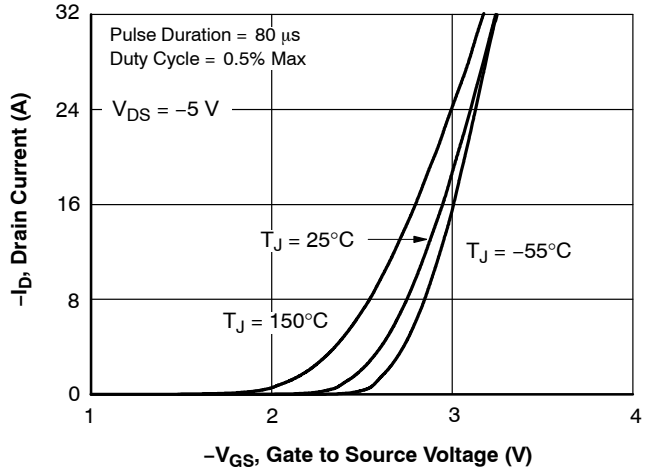


Figure 5. Transfer Characteristics

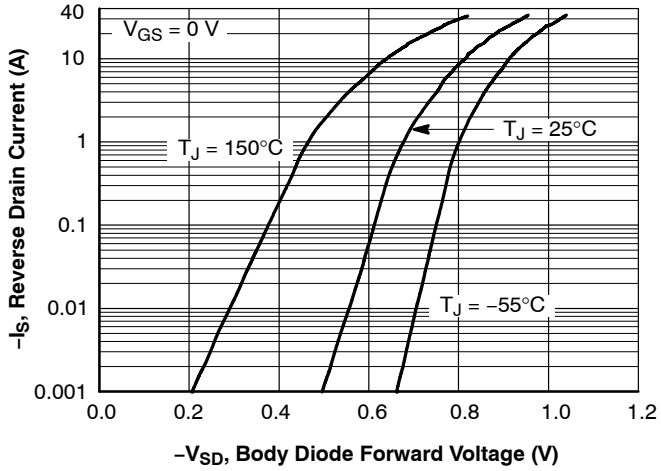


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

TYPICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted) (continued)

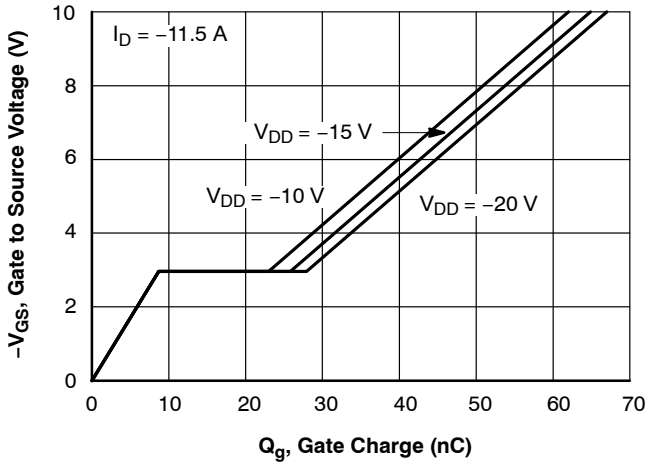


Figure 7. Gate Charge Characteristics

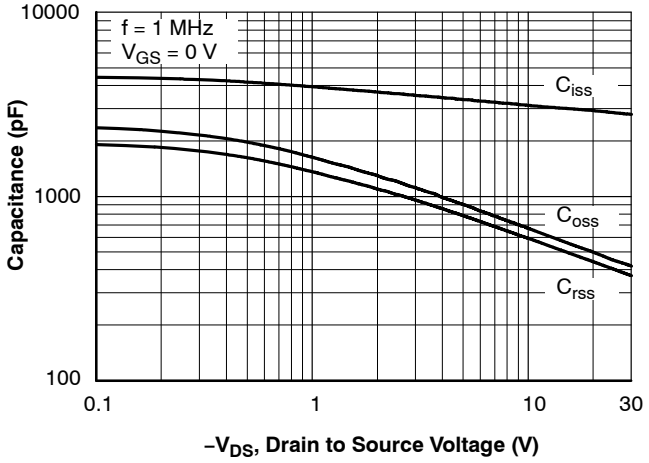


Figure 8. Capacitance vs. Drain to Source Voltage

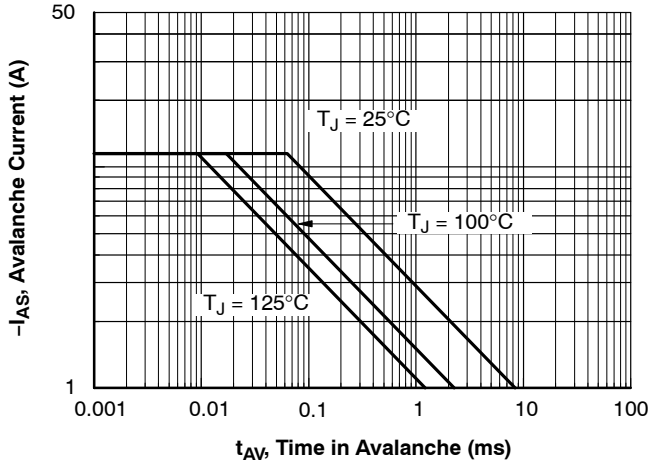


Figure 9. Unclamped Inductive Switching Capability

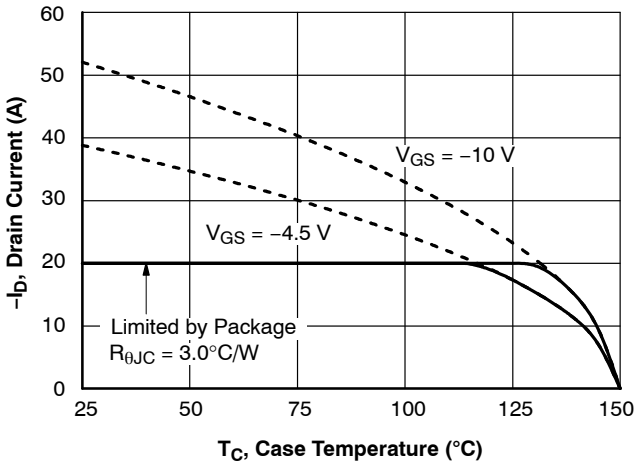


Figure 10. Maximum Continuous Drain Current vs Case Temperature

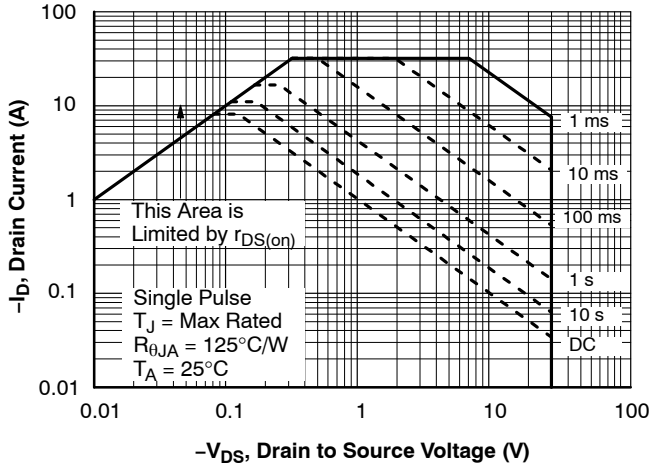


Figure 11. Forward Bias Safe Operating Area

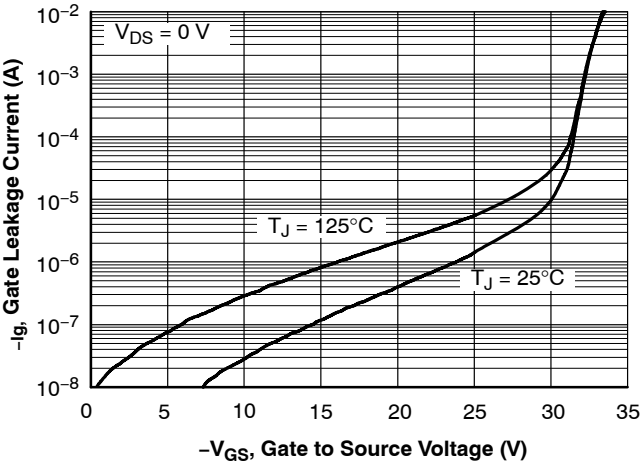


Figure 12. Igss vs. Vgss

TYPICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted) (continued)

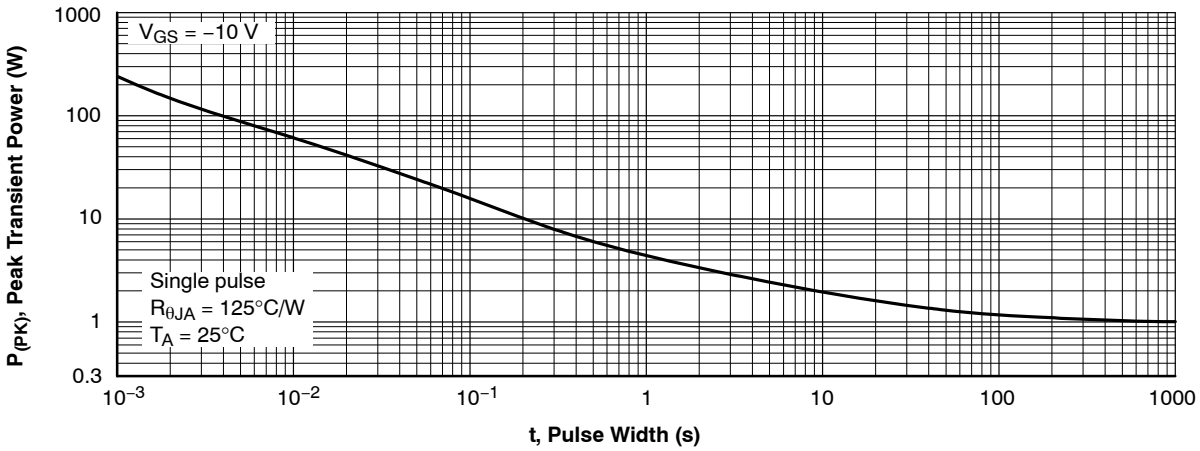


Figure 13. Single Pulse Maximum Power Dissipation

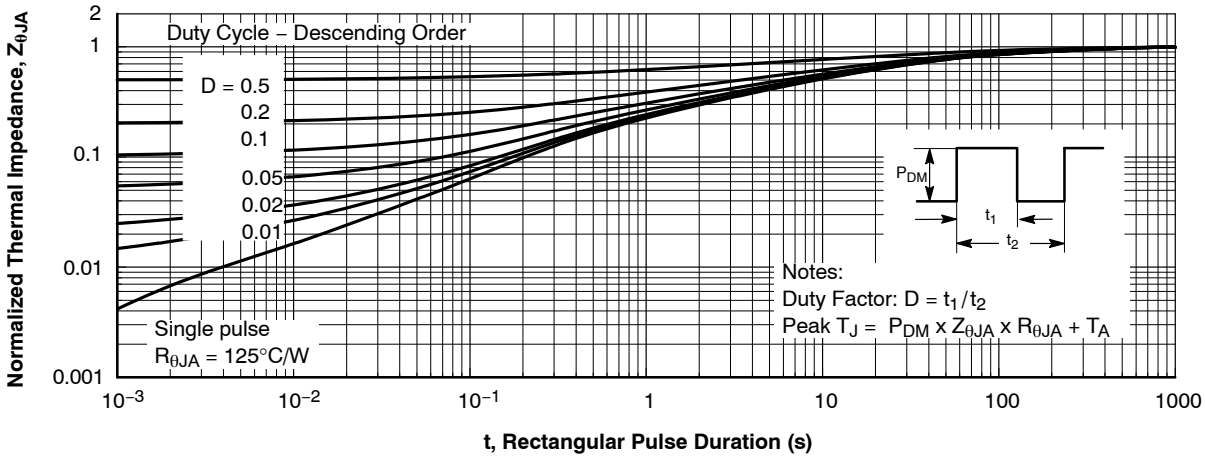


Figure 14. Junction−to−Ambient Transient Thermal Response Curve

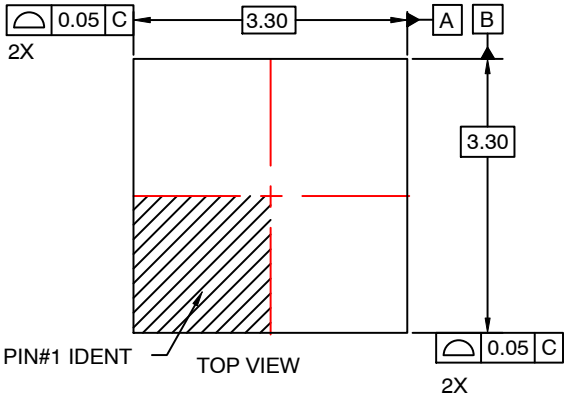
ORDERING INFORMATION

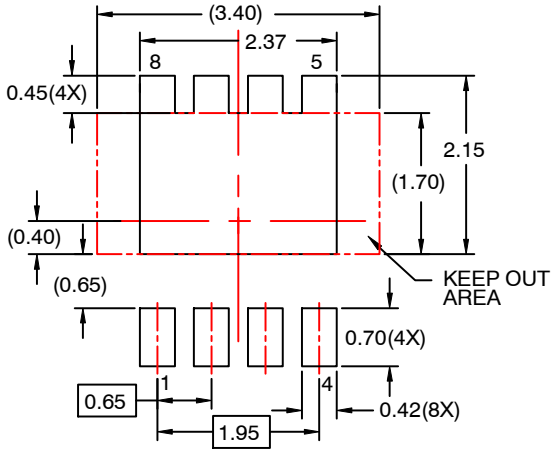
Device	Device Marking	Package Type	Shipping†
FDMC6679AZ	FDMC6679AZ	WDFN8 3.3x3.3, 0.65P, Case 511DH (Pb−Free)	3000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

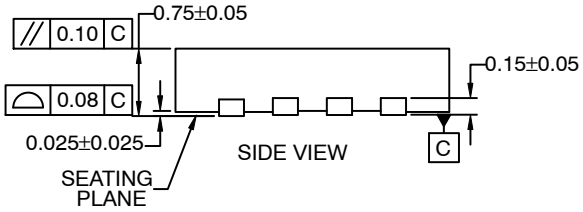
WDFN8 3.3x3.3, 0.65P
CASE 511DH
ISSUE O

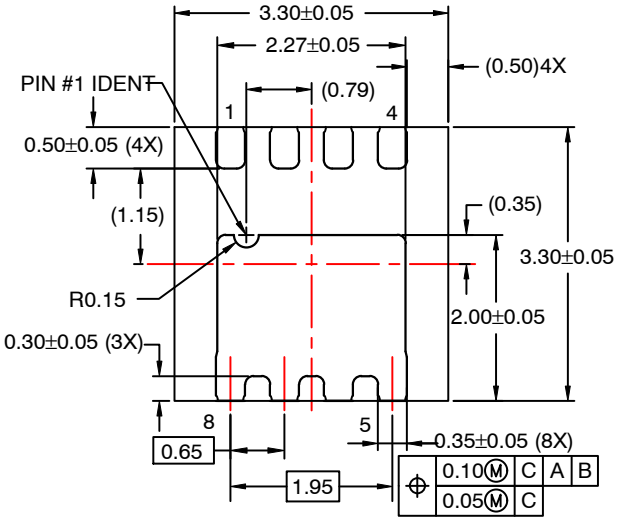
DATE 31 JUL 2016





RECOMMENDED LAND PATTERN





BOTTOM VIEW

NOTES:

A. DOES NOT CONFORM TO JEDEC REGISTRATION MO−229

B. DIMENSIONS ARE IN MILLIMETERS.

C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.

D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN.

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